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# Terahertz-driven phonon upconversion in SrTiO<sub>3</sub>

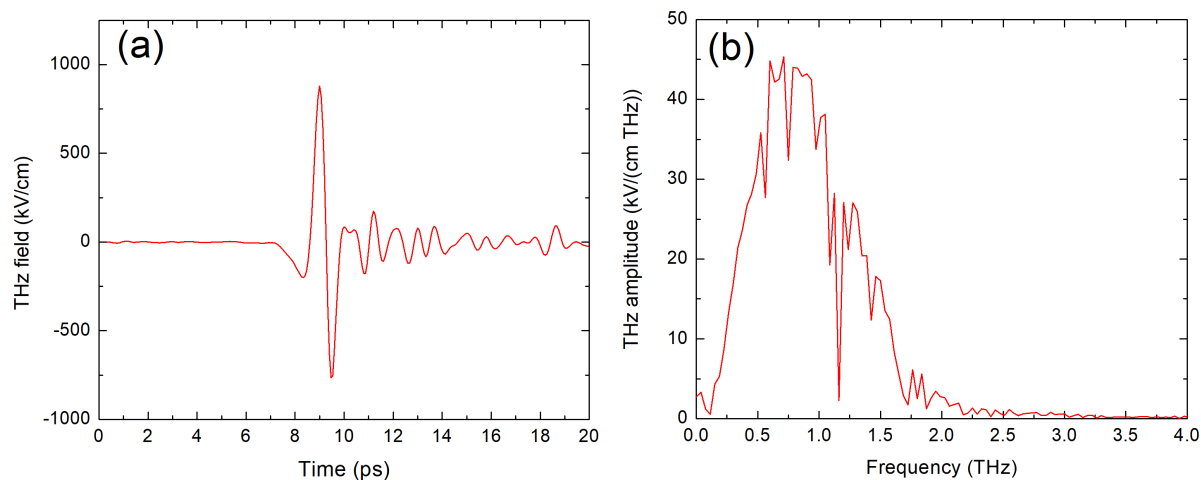
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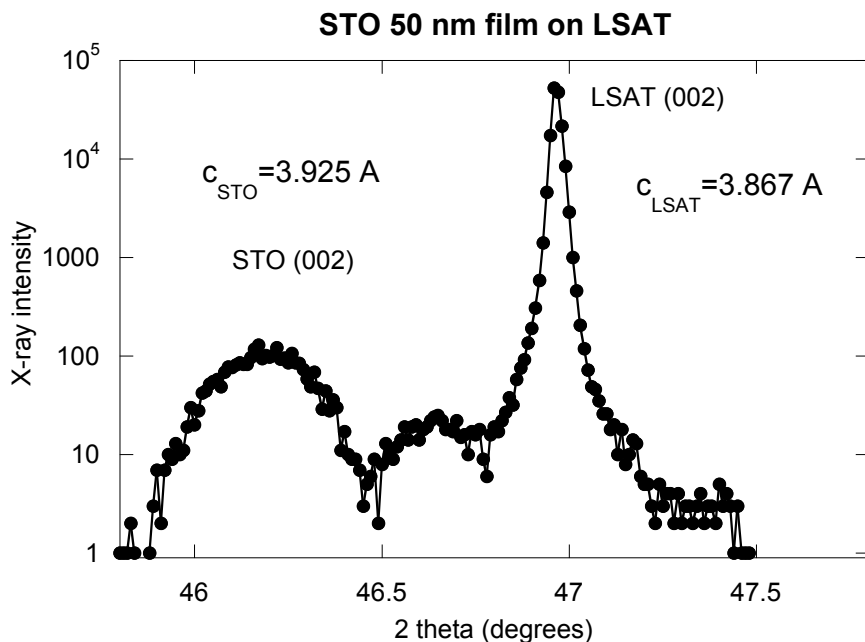
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# Supplementary Information

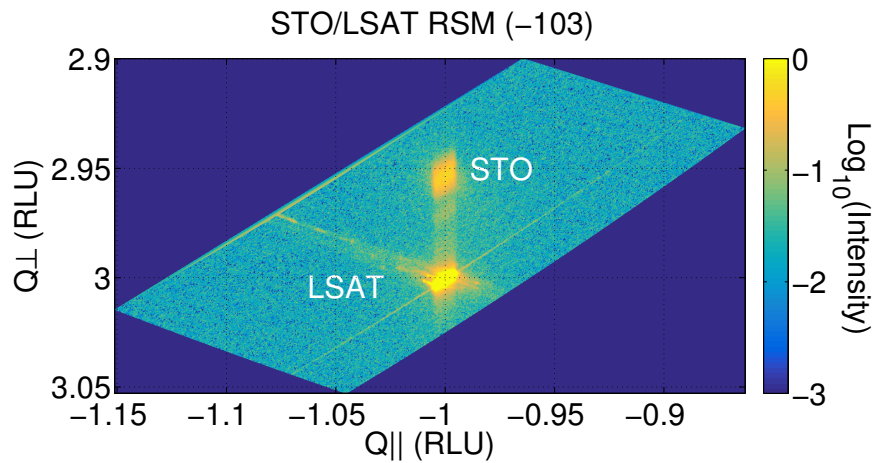
Kozina et al, "Terahertz-Driven Phonon Upconversion in SrTiO<sub>3</sub>"



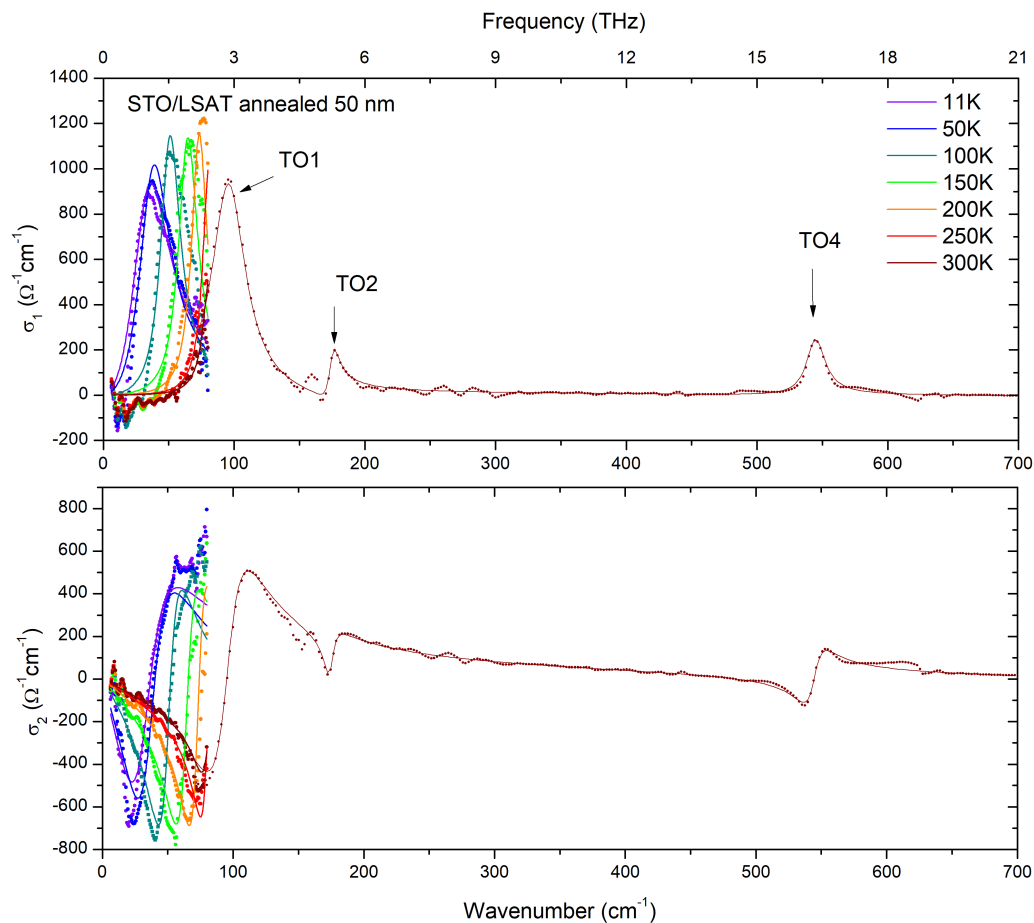
**Figure S1 Terahertz pump waveform:** **a** Electro-optic sampling signal of terahertz (THz) pump at sample location measured in-situ by electro-optic sampling in a 50  $\mu\text{m}$  thick (110) GaP crystal. **b** Magnitude of frequency spectrum of the THz waveform in **a** calculated by Fast Fourier Transform. The intensity was adjusted with wiregrid polarizers (Infraspecs P01) without changing the THz waveform.



**Figure S2: Two-Theta scan of sample before annealing.** Static x-ray diffraction pattern along sample normal. The low-angle peak corresponds to the STO film and the sharp peak at higher angle is the LSAT substrate. We observe clear splitting along the cross-plane direction between the substrate and the film. These measurements were taken before the sample was annealed.



**Figure S3: Reciprocal space map of the sample before annealing.** Static reciprocal space map collected on a similar sample prior to annealing about the  $(-1\ 0\ 3)$  reciprocal lattice point using a  $\text{Cu } \alpha$  source. The separation between the film and substrate peaks along the cross-plane direction shows there is a difference in lattice parameter, whereas there is clear indication that in-plane the film and substrate are lattice matched to the LSAT unit cell.



**Figure S4: Optical conductivity of the annealed sample.** We show additional ellipsometry measurements on our sample incorporating extra temperature points at low and high temperature. The extended frequency range at 300K shows the  $\text{TO}_2$  and  $\text{TO}_4$  phonon modes. Data from Fig. 3a are also included for comparison.

	Sr	Ti	Oxy	Ozx	Oyz
X	0	0.5	0.5	0.5	0
Y	0	0.5	0.5	0	0.5
Z	0.00987045	0.51190984	0.9970011	0.4956093	0.4956093

**Table S1 Unit Cell Relative Coordinates from DFT.** Lattice is tetragonal with  $a_0 = 3.89000 \text{ \AA}$  and  $c_0 = 3.91043 \text{ \AA}$ .

	Sr	Ti	Oxy	Ozx	Oyz
X	0.02963898	0.04544241	-0.08189972	-0.09030182	-0.07348941
Y	-0.02957567	-0.04530107	0.08204853	0.07359076	0.09041028
Z	0	0	0	0	0

**Table S2 Eigenvector for  $Q_1$  mode.** Eigenvector calculated with  $E_{\text{THz}}$  parallel to  $(X, -Y, 0)$ . The units of the eigenvector are  $\text{\AA}^* \text{AMU}^{1/2}$ . The eigenvector is normalized so that  $\sum \xi_{ijk}^2 m_{jk} = 1$ . Here  $\xi_{ijk}$  and  $m_{jk}$  are the eigenvector and ion mass in AMU, and the indices  $i, j, k$  label the eigenvector mode, ion, and coordinate direction.

	Sr	Ti	Oxy	Ozx	Oyz
X	-0.04831474	0.07770832	0.01575631	0.00874036	0.00874793
Y	0.04829799	-0.07773579	-0.01568512	-0.00870886	-0.00868356
Z	0	0	0	0	0

**Table S3 Eigenvector for  $Q_2$  mode.** Eigenvector calculated with  $E_{\text{THz}}$  parallel to  $(X, -Y, 0)$ . The units of the eigenvector are  $\text{\AA}^* \text{AMU}^{1/2}$ . The eigenvector is normalized so that  $\sum \xi_{ijk}^2 m_{jk} = 1$ . Here  $\xi_{ijk}$  and  $m_{jk}$  are the eigenvector and ion mass in AMU, and the indices  $i, j, k$  label the eigenvector mode, ion, and coordinate direction.

$\omega_1/(2\pi)$	<b>1.669 THz</b>	$\kappa_1$	$8900 \text{ THz}^2 \text{\AA}^{-2} \text{AMU}^{-1}$	$\chi$	$4000 \text{ THz}^2 \text{\AA}^{-2} \text{AMU}^{-1}$
$\omega_2/(2\pi)$	<b>5.186 THz</b>	$\kappa_2$	<b><math>1066 \text{ THz}^2 \text{\AA}^{-2} \text{AMU}^{-1}</math></b>	$\psi_{12}$	$-4000 \text{ THz}^2 \text{\AA}^{-2} \text{AMU}^{-1}$
$\gamma_1/(2\pi)$	<b>0.900 THz</b>	$Z_1^*$	<b><math>2.6 \text{ e}^- \text{AMU}^{-1/2}</math></b>	$\psi_{21}$	<b><math>-841 \text{ THz}^2 \text{\AA}^{-2} \text{AMU}^{-1}</math></b>
$\gamma_2/(2\pi)$	0.150 THz	$Z_2^*$	<b><math>0.2 \text{ e}^- \text{AMU}^{-1/2}</math></b>	$\beta$	0.215

**Table S4 Model parameters.** Values in bold are unmodified from DFT calculations at 0 K. Values in red were extracted from spectroscopy and literature. Parameters  $\kappa_1$ ,  $\psi_{12}$ , and  $\chi$  were initially established by DFT and then tuned to best fit the experimental data. The parameter  $\beta$  was informed by calculations for the expected field screening inside the STO film on the LSAT substrate but was fine-tuned to best fit the experimental data. The linewidth  $\gamma_2$  was estimated from the trXRD data in the frequency domain.

## Comments on Mode Symmetry in STO Film

In bulk STO, there are four sets of optical phonons, with symmetries (in order of increasing frequency)  $T_{1u}$ ,  $T_{1u}$ ,  $T_{2u}$ , and  $T_{1u}$  [S1]. The three  $T_{1u}$  modes are all IR active and in addition possess LO/TO splitting. The  $T_{2u}$  mode is known as “silent” because it lacks both IR and Raman activity [S2]. This mode lacks TO/LO splitting. The mode frequencies at 85K are presented in Table S5 and labeled according to [S3].

Mode	Frequency (cm <sup>-1</sup> )	Frequency (THz)
TO <sub>1</sub> (soft)	31	0.93
LO <sub>1</sub>	170.6	5.114
TO <sub>2</sub>	172.5	5.171
T <sub>2u</sub> (TO <sub>3</sub> , LO <sub>2</sub> ) (silent)	265	7.94
LO <sub>3</sub>	469.5	14.08
TO <sub>4</sub>	544	16.3
LO <sub>4</sub>	801	24.0

*Table S5 Bulk STO Mode Frequencies at 85 K. Values are extracted from Barker [S3].*

In our film, however, the substrate is compressive and makes the STO film slightly tetragonal (see static x-ray characterization in Figure S2). This changes the space group to  $P4mm$  and the point group at zone center to  $4mm$  ( $C_{4v}$ ). Therefore this alters the symmetries of the four modes according to the rules:  $T_{1u} \rightarrow A_1 + E$ ,  $T_{2u} \rightarrow B_1 + E$ . The  $A_1$  and  $B_1$  modes consist of displacements along the cross-plane component, while the  $E$  modes consist of displacements in-plane. This splitting should also adjust the frequencies of the modes.

The incident THz field resonantly couples to a near-zone center transverse optical mode (the soft mode) with displacement along the THz polarization direction,  $[1 -1 0]$ , and with wavevector parallel to the THz wavevector (cross-plane direction). Thus the excited soft mode has displacement vector along  $[1,-1,0]$  and wavevector along  $[0 0 1]$ , and has symmetry  $E$ . In addition to observing this feature in our trXRD signal, we also detect oscillations at 5.15 THz and 7.6 THz, close in frequency to the LO<sub>1</sub>/TO<sub>2</sub> and T<sub>2u</sub> (silent) modes in bulk STO.

By symmetry, we can only couple the  $E$ -symmetry soft mode to other modes of symmetry  $E$  by a fourth-order coupling term (e.g.  $Q_1^2 Q_2^2$  or  $Q_1^3 Q_2$ ). Additionally, our x-ray scattering geometry is only sensitive to motion with some component parallel to the x-ray scattering vector, along  $[2 -2 3]$ . In-plane, this corresponds to the  $[1 -1 0]$  direction.

Thus, while we can couple to  $E$  modes with polarization along  $[1 1 0]$  we cannot detect them with our choice of x-ray scattering geometry. Our x-ray scattering geometry is also sensitive to displacements in the cross-plane direction  $[0 0 1]$  however these modes are symmetry  $A_1$  and therefore require a different coupling term. Specifically, at lowest order we would have either  $Q_1^2 Q_2$  and then  $Q_1^4 Q_2$ . These features would manifest respectively as signal at  $2 * \omega_1/2\pi$  (3.3 THz) and  $4 * \omega_1/2\pi$  (6.7 THz) which we do not observe.

Hence we attribute the oscillatory components at 5.15 and 7.6 THz in our x-ray scattering signal to transverse optical phonons with symmetry  $E$  with displacements along  $[1 -1 0]$

and wavevectors along  $[0\ 0\ 1]$ . We then label these three coupled modes as  $TO_1$ ,  $TO_2$ , and  $TO_3$  in order of increasing frequency. Note that from our numerical calculations of the nonlinear phonon coupling terms, we find that  $T_{1u}(\text{soft}) \rightarrow T_{2u}(\text{silent})$  coupling while possible is much weaker than  $E(\text{soft}) \rightarrow E(\text{silent})$ .

References:

S1. Cowley, R. A. Lattice Dynamics and Phase Transitions of Strontium Titanate. *Phys. Rev.* **134**, A981–A997 (1964).

S2. Denisov, V. N., Mavrin, B. N., Podobedov, V. B. & Scott, J. F. Hyper-Raman Spectra and Frequency Dependence of Soft Mode Damping in SrTiO<sub>3</sub>. *J. Raman Spectrosc.* **14**, 276–283 (1983).

S3. Barker, A. S. Temperature dependence of the transverse and longitudinal optic mode frequencies and charges in SrTiO<sub>3</sub> and BaTiO<sub>3</sub>. *Phys. Rev.* **145**, 391–399 (1966).